



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Shimpei MIURA et al.

Application No.: 10/714,645

Filed: November 18, 2003

Docket No.: 116909

For: FLUID LEAKAGE DETECTION APPARATUS AND FLUID LEAKAGE DETECTION METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. English-language Abstracts of the non-English language references are attached hereto. (Refs. 1-3)
- ☒ 3. Computer-generated English translations of the following Japanese Patent Publication have been obtained from the website of the Japanese Patent Office (<http://www.jpo.go.jp>), and are attached, but have not been reviewed for accuracy. See References 1-2.

Respectfully submitted,

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Date: February 18, 2004

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(REV. 8-83)US Dept. of Commerce
PATENT & TRADEMARK OFFICEATTY DOCKET NO.
116909APPLICATION NO.
10/714,645

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANTS
Shimpei MIURA et al.FILING DATE
November 18, 2003

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
	1	JP A 2002-227727 w/ abst & trans	08/14/2002	Japan		
	2	JP A 2001-159375 w/ abst & trans	06/12/2001	Japan		
	3	JP A 2-176440 w/ abst	07/09/1990	Japan		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: February 18, 2004